

Search Notes

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David E. Bochna

Applicant(s)/Patent under
Reexamination

HANEY ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
285	390, 333	8/22/2006	DB
	334, 115		
	423		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated the previous search	8/22/2006	DB